

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at www.onsemi.com

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, emplo



December 2015

FDP075N15A / FDB075N15A N-Channel PowerTrench® MOSFET 150 V, 130 A, 7.5 m Ω

Features

- $R_{DS(on)}$ = 6.25 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 100 A
- · Fast Switching
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low R_{DS(on)}
- · High Power and Current Handling Capability
- · RoHS Compliant

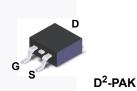
Description

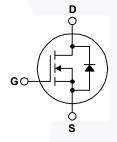
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

Applications

- · Synchronous Rectification for ATX / Server / Telecom PSU
- · Battery Protection Circuit
- · Motor Drives and Uninterruptible Power Supplies
- · Micro Solar Inverter







MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter			FDP075N15A_F102 FDB075N15A	Unit	
V _{DSS}	Drain to Source Voltage			150	V	
V	Cata to Source Voltage	- DC		±20	V	
V_{GSS}	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	v	
I _D	Drain Current	- Continuous (T _C = 25°C)		130*	A	
	Diam Current	- Continuous (T _C = 100°C)		92		
I _{DM}	Drain Current	- Pulsed	(Note 1)	522	Α	
E _{AS}	Single Pulsed Avalanche Energ	у	(Note 2)	588	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	6.0	V/ns	
D	Dower Dissination	$(T_C = 25^{\circ}C)$		333	W	
P_D	Power Dissipation	- Derate Above 25°C		2.22	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +175	οС	
TL	Maximum Lead Temperature fo	r Soldering, 1/8" from Case for 5 Seconds		300	οС	

^{*} Package limitation current is 120 A.

Thermal Characteristics

Symbol	Parameter	FDP075N15A_F102 FDB075N15A	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.45	
D	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	62.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, D2-PAK (1 in ² Pad of 2-oz Copper), Max.	40	

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDP075N15A_F102	FDP075N15A	TO-220	Tube	N/A	N/A	50 units
FDB075N15A	FDB075N15A	D ² -PAK	Tape and Reel	330 mm	24 mm	800 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$	150	-	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C	-	0.1	-	V/°C
	Zero Gate Voltage Drain Current	V _{DS} = 120 V, V _{GS} = 0 V	-	-	1	^
I _{DSS}	Zero Gate voltage Drain Current	$V_{DS} = 120 \text{ V}, T_{C} = 150^{\circ}\text{C}$	-	-	500	μΑ
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	-	4.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 100 A	-	6.25	7.5	$m\Omega$
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 100 A	-	164	1	S

Dynamic Characteristics

C _{iss}	Input Capacitance	75.77.77		-	5525	7350	pF
Coss	Output Capacitance	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz		-\	516	685	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 WII 12		- \	21	-	pF
C _{oss(er)}	Energy Related Output Capacitance	V _{DS} = 75 V, V _{GS} = 0 V		- \	909	-	pF
Q _{g(tot)}	Total Gate Charge at 10V			-	77	100	nC
Q_{gs}	Gate to Source Gate Charge	V _{DS} = 75 V, I _D = 100 A,		-	26	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau	V _{GS} = 10 V		-	11	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	()	Note 4)	-	16	-	nC
ESR	Equivalent Series Resistance(G-S)	f = 1 MHz		-	2.29	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	28	66	ns
t _r	Turn-On Rise Time	$V_{DD} = 75 \text{ V}, I_D = 100 \text{ A},$	-	37	84	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{G} = 4.7 \Omega$	_	62	134	ns
t _f	Turn-Off Fall Time	(Note 4)	-	21	52	ns

Drain-Source Diode Characteristics

Is	Maximum Continuous Drain to Source Diode Forward Current		-	130*	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	520	Α
V_{SD}	Drain to Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_{SD} = 100 \text{ M}$) A -	-	1.25	V
t _{rr}	Reverse Recovery Time $V_{GS} = 0 \text{ V}, V_{DD} = 79$	5 V, I _{SD} = 100 A, -	97	-	ns
Q _{rr}	Reverse Recovery Charge $dI_F/dt = 100 A/\mu s$	-	264	//-	nC

Notes

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2. Starting $T_J = 25$ °C, L = 3 mH, $I_{AS} = 19.8$ A.
- 3. I $_{SD} \leq$ 100 A, di/dt \leq 200 A/µs, V $_{DD} \leq$ BV $_{DSS}$, starting T $_{J}$ = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

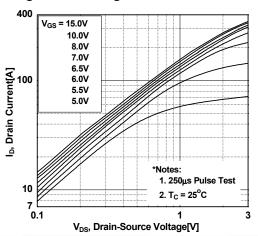


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

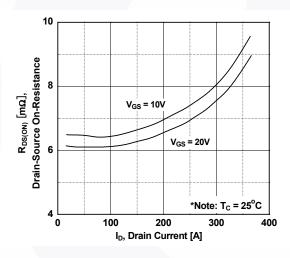


Figure 5. Capacitance Characteristics

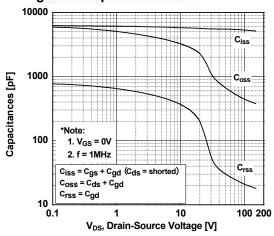


Figure 2. Transfer Characteristics

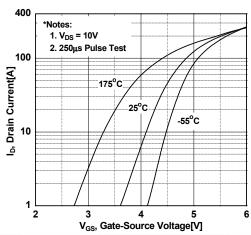


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

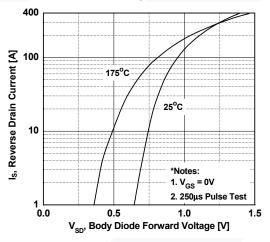
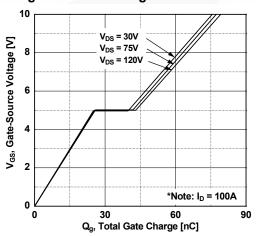


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

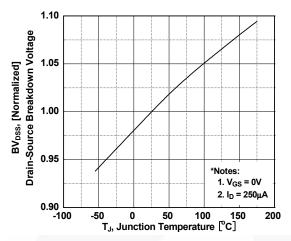


Figure 9. Maximum Safe Operating Area

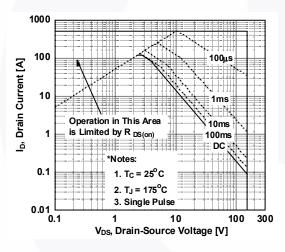


Figure 11. Eoss vs. Drain to Source Voltage

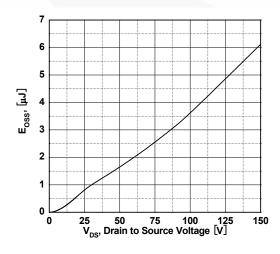


Figure 8. On-Resistance Variation vs. Temperature

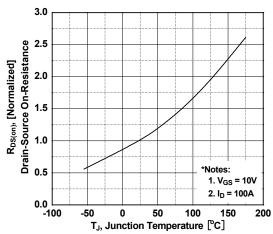


Figure 10. Maximum Drain Current vs. Case Temperature

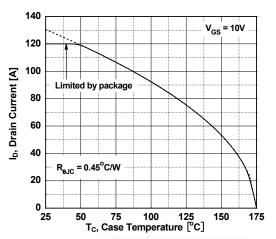
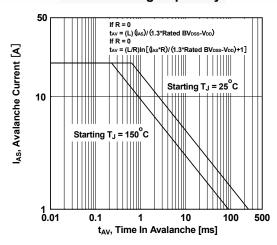
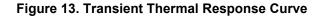
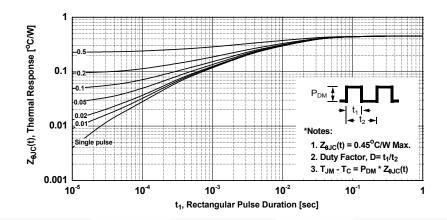


Figure 12. Unclamped Inductive Switching Capability



Typical Performance Characteristics (Continued)





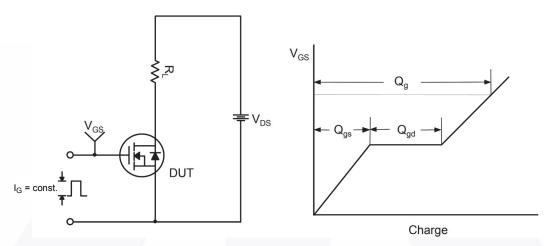


Figure 14. Gate Charge Test Circuit & Waveform

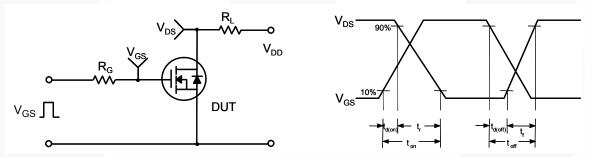


Figure 15. Resistive Switching Test Circuit & Waveforms

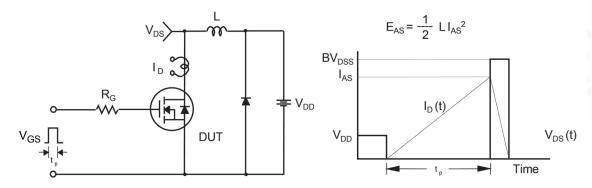


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms

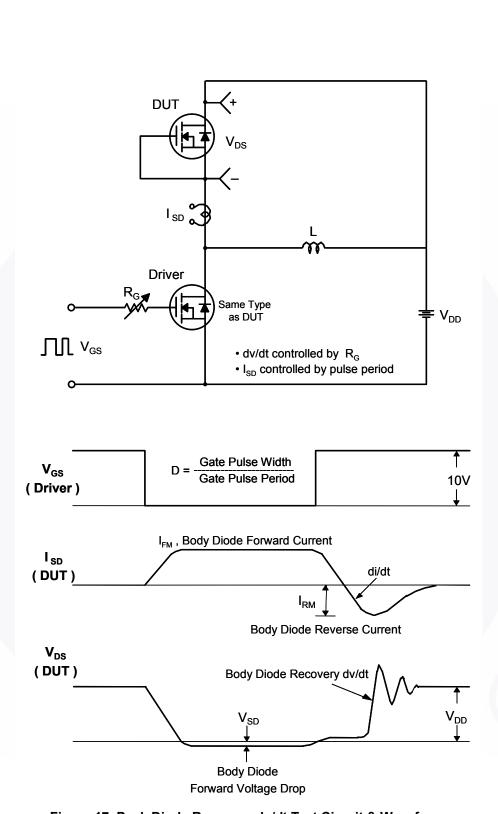
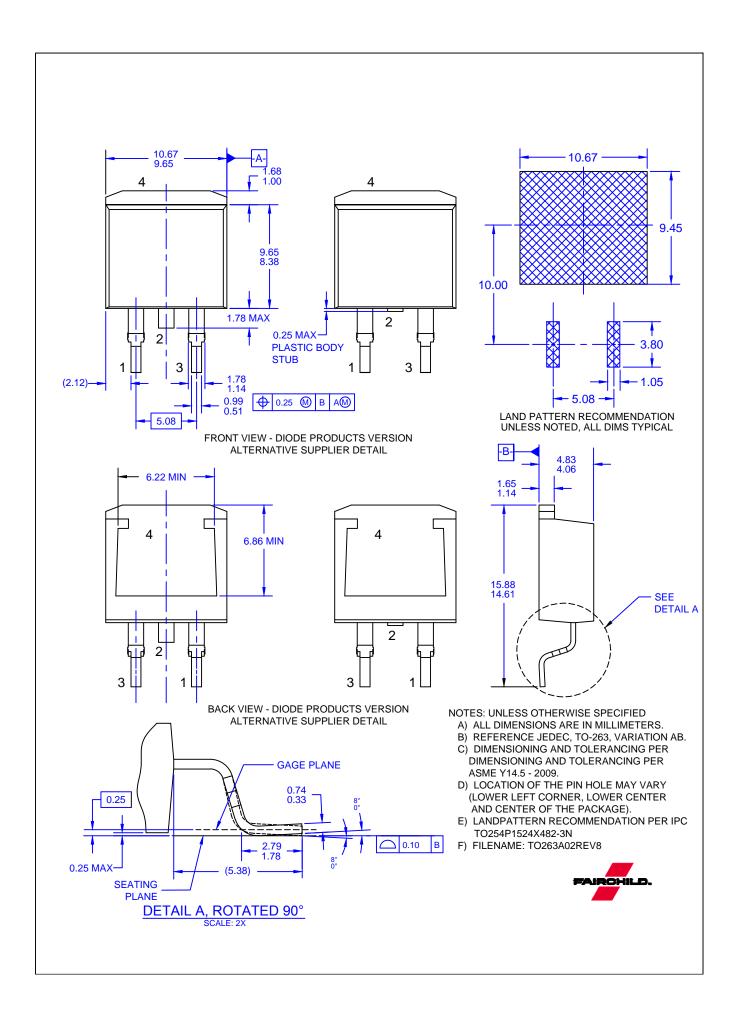
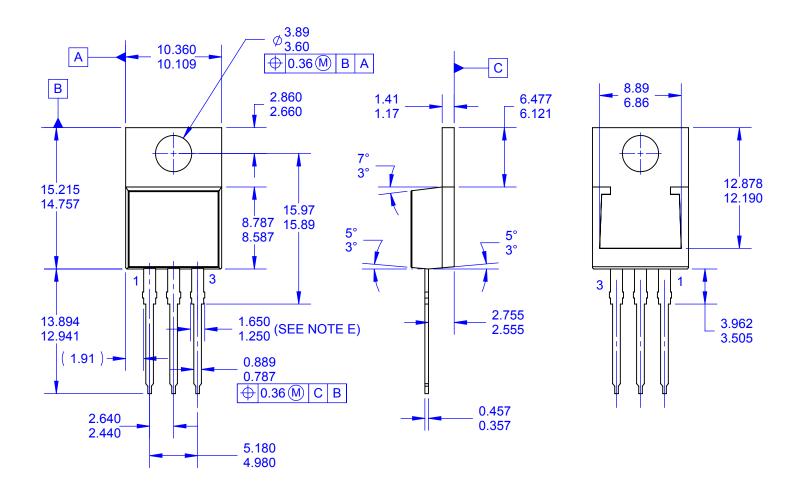
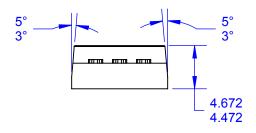


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms







NOTES:

- A. PACKAGE REFERENCE: JEDEC TO220 **VARIATION AB**
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSION AND TOLERANCE AS PER ASME Y14.5-2009.
- D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.
- E. MAX WIDTH FOR F102 DEVICE = 1.35mm. F. DRAWING FILE NAME: TO220T03REV4.
- G. FAIRCHILD SEMICONDUCTOR.

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support:
Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative